

## DIM1800ESM12-A000

## **Single Switch IGBT Module**

Replaces July 2002, version DS5529-2.1

DS5529-3.0 March 2003

#### **FEATURES**

- 10µs Short Circuit Withstand
- High Thermal Cycling Capability
- Non Punch Through Silicon
- Isolated MMC Base with AIN Substrates

#### **APPLICATIONS**

- High Reliability Inverters
- Motor Controllers
- Traction Drives

The Powerline range of high power modules includes half bridge, chopper, dual, single and bi-directional switch configurations covering voltages from 600V to 3300V and currents up to 2400A.

The DIM1800ESM12-A000 is a single switch 1200V, n channel enhancement mode, insulated gate bipolar transistor (IGBT) module. The IGBT has a wide reverse bias safe operating area (RBSOA) plus full 10µs short circuit withstand. This module is optimised for applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

#### **ORDERING INFORMATION**

Order As:

## DIM1800ESM12-A000

Note: When ordering, please use the whole part number.

#### **KEY PARAMETERS**

V <sub>CES</sub>		1200V
V <sub>CE(sat)</sub> *	(typ)	2.2V
I <sub>C</sub>	(max)	1800A
I <sub>C(PK)</sub>	(max)	3600A

<sup>\*(</sup>measured at the power busbars and not the auxiliary terminals)

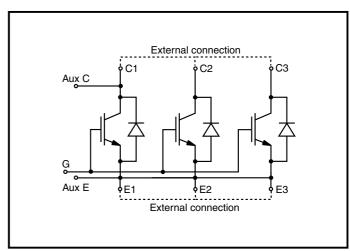


Fig. 1 Single switch circuit diagram

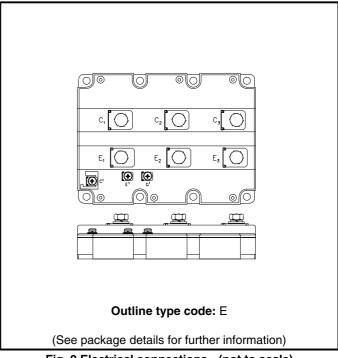


Fig. 2 Electrical connections - (not to scale)



### **ABSOLUTE MAXIMUM RATINGS**

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

T<sub>case</sub> = 25°C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
V <sub>CES</sub>	Collector-emitter voltage	$V_{GE} = 0V$	1200	٧
$V_{GES}$	Gate-emitter voltage	-	±20	V
I <sub>c</sub>	Continuous collector current	T <sub>case</sub> = 85°C	1800	Α
I <sub>C(PK)</sub>	Peak collector current	1ms, T <sub>case</sub> = 115°C	3600	Α
$P_{\text{max}}$	Max. transistor power dissipation	$T_{case} = 25^{\circ}C, T_{j} = 150^{\circ}C$	15625	W
l <sup>2</sup> t	Diode I <sup>2</sup> t value (IGBT arm)	$V_R = 0, t_p = 10 \text{ms}, T_{vj} = 125^{\circ}\text{C}$	900	kA <sup>2</sup> s
V <sub>isol</sub>	Isolation voltage - per module	Commoned terminals to base plate. AC RMS, 1 min, 50Hz	2500	٧
$Q_{PD}$	Partial discharge - per module	IEC1287. V <sub>1</sub> = 1300V, V <sub>2</sub> = 1000V, 50Hz RMS	10	PC



### THERMAL AND MECHANICAL RATINGS

Internal insulation material: AIN
Baseplate material: AISiC
Creepage distance: 32mm
Clearance: 20mm
CTI (Critical Tracking Index): 175

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
R <sub>th(j-c)</sub>	Thermal resistance - transistor	Continuous dissipation -	-	-	8	°C/kW
		junction to case				
R <sub>th(j-c)</sub>	Thermal resistance - diode	Continuous dissipation -	-	-	17.8	°C/kW
		junction to case				
R <sub>th(c-h)</sub>	Thermal resistance - case to heatsink	Mounting torque 5Nm	-	-	6	°C/kW
	(per module)	(with mounting grease)				
T <sub>j</sub>	Junction temperature	Transistor	-	-	150	°C
		Diode	-	-	125	°C
T <sub>stg</sub>	Storage temperature range	-	-40	-	125	°C
-	Screw torque	Mounting - M6	-	-	5	Nm
		Electrical connections - M4	-	-	2	Nm
		Electrical connections - M8	-	-	10	Nm



### **ELECTRICAL CHARACTERISTICS**

 $T_{case} = 25$ °C unless stated otherwise.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
I <sub>CES</sub>	Collector cut-off current	$V_{GE} = 0V$ , $V_{CE} = V_{CES}$	-	-	3	mA
		$V_{GE} = 0V, V_{CE} = V_{CES}, T_{case} = 125^{\circ}C$	-	-	75	mA
I <sub>GES</sub>	Gate leakage current	$V_{GE} = \pm 20V, V_{CE} = 0V$	-	-	12	μА
V <sub>GE(TH)</sub>	Gate threshold voltage	$I_{\rm C} = 90$ mA, $V_{\rm GE} = V_{\rm CE}$	4.5	5.5	6.5	٧
V <sub>CE(sat)</sub> †	Collector-emitter saturation voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 1800A	-	2.2	2.8	٧
		$V_{GE} = 15V, I_{C} = 1800A, T_{case} = 129$	5°C -	2.6	3.3	V
I <sub>F</sub>	Diode forward current	DC	-	-	1800	Α
I <sub>FM</sub>	Diode maximum forward current	t <sub>p</sub> = 1ms	-	-	3600	Α
V <sub>F</sub> †	Diode forward voltage	I <sub>F</sub> = 2400A	-	2.1	2.4	٧
		I <sub>F</sub> = 2400A, T <sub>case</sub> = 125°C	-	2.1	2.4	٧
C <sub>ies</sub>	Input capacitance	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 1MHz	-	200	-	nF
L <sub>M</sub>	Module inductance	-	-	10	-	nH
R <sub>INT</sub>	Internal transistor resistance	-	-	0.09	-	mΩ
SC <sub>Data</sub>	Short circuit. I <sub>sc</sub>	$T_j = 125^{\circ}C, V_{CC} = 900V,$ $I_1$	-	12500	-	Α
		$t_p \le 10\mu s$ , $V_{CE(max)} = V_{CES} - L^*$ . di/dt	-	10000	-	Α
		IEC 60747-9				

### Note:

 $<sup>^{\</sup>scriptscriptstyle \dagger}$  Measured at the power busbars and not the auxiliary terminals

 $L^*$  is the circuit inductance +  $L_M$ 



### **ELECTRICAL CHARACTERISTICS**

# $T_{case} = 25^{\circ}C$ unless stated otherwise

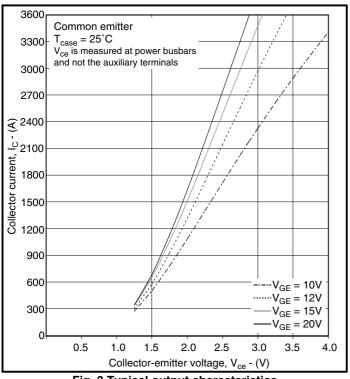
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 1800A	-	1250	-	ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$	-	190	-	ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 600V	-	330	-	mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = R_{G(OFF)} = 1.2\Omega$	-	220	-	ns
t <sub>r</sub>	Rise time	L ~ 60nH	-	200	-	ns
E <sub>o</sub>	Turn-on energy loss		-	100	-	mJ
$Q_g$	Gate charge		-	20	-	μС
Q <sub>rr</sub>	Diode reverse recovery charge	$I_{\rm F} = 1800 {\rm A}, \ V_{\rm R} = 50\% \ V_{\rm CES},$	-	210	-	μС
I <sub>rr</sub>	Diode reverse current	dI <sub>F</sub> /dt = 9000A/μs	-	860	-	Α
E <sub>REC</sub>	Diode reverse recovery energy		-	110	-	mJ

# T<sub>case</sub> = 125°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 1800A	-	1450	-	ns
t <sub>r</sub>	Fall time	$V_{GE} = \pm 15V$	-	190	-	ns
E <sub>OFF</sub>	Turn-off energy loss	V <sub>CE</sub> = 600V	-	390	-	mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = R_{G(OFF)} = 1.2\Omega$	-	230	-	ns
t,	Rise time	L ~ 60nH	-	340	-	ns
E <sub>on</sub>	Turn-on energy loss		-	180	-	mJ
Q <sub>rr</sub>	Diode reverse recovery charge	$I_F = 1800A, V_R = 50\% V_{CES},$	-	390	-	μС
I <sub>rr</sub>	Diode reverse current	dl <sub>F</sub> /dt = 8000A/μs	-	1100	-	Α
E <sub>REC</sub>	Diode reverse recovery energy		-	200	-	mJ

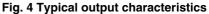


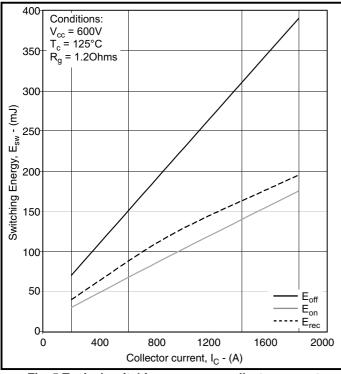
### **TYPICAL CHARACTERISTICS**

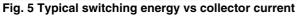


Common emitter T<sub>case</sub> = 125°C V<sub>ce</sub> is measured at power busbars and not the auxiliary terminals 3300 3000 2700 €2400 <u></u>2100 Collector current, 1800 1500 1200 900 600  $V_{GE} = 10V$  $V_{GE} = 12V$ 300  $V_{GE} = 15V$  $V_{GE} = 20V$ 0 0.5 2.0 2.5 3.0 3.5 4.0 4.5 5.0 Collector-emitter voltage,  $V_{ce}$  - (V)

Fig. 3 Typical output characteristics







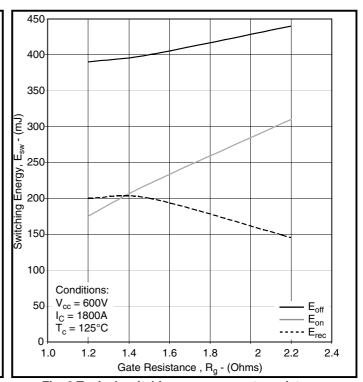
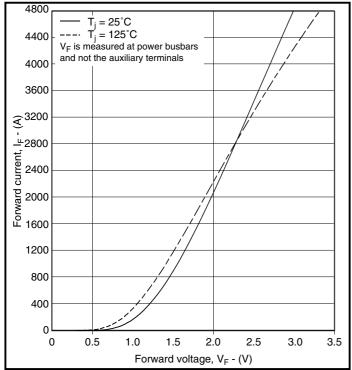


Fig. 6 Typical switching energy vs gate resistance





2400 2200 Collector current, 2000 1800 1600 1400 1200 1000 800  $T_{case} = 125^{\circ}C$  $V_{ge} = 15V$ 600  $R_g = 1.2 \text{ Ohms}$ 400 Module I<sub>C</sub> 200 Chip  $I_{\mathbb{C}}$ 100 200 300 400 500 600 700 800 900 1000 1100 1200 1300 Collector emitter voltage,  $V_{ce}$  - (V)

3800

3600

3400

3200

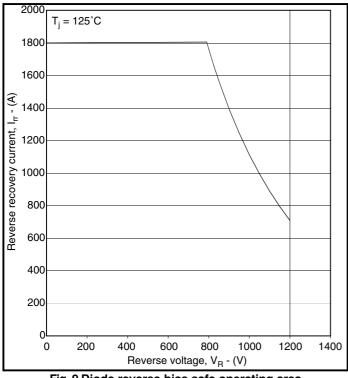
3000

2800

2600

Fig. 7 Diode typical forward characteristics

Fig. 8 Reverse bias safe operating area





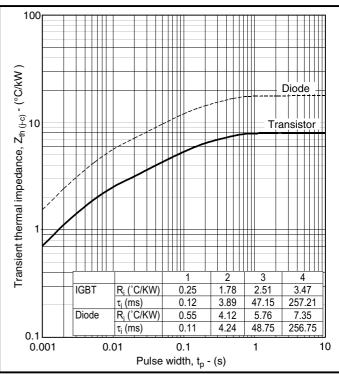


Fig. 10 Transient thermal impedance



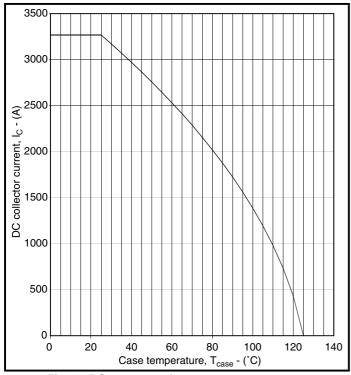
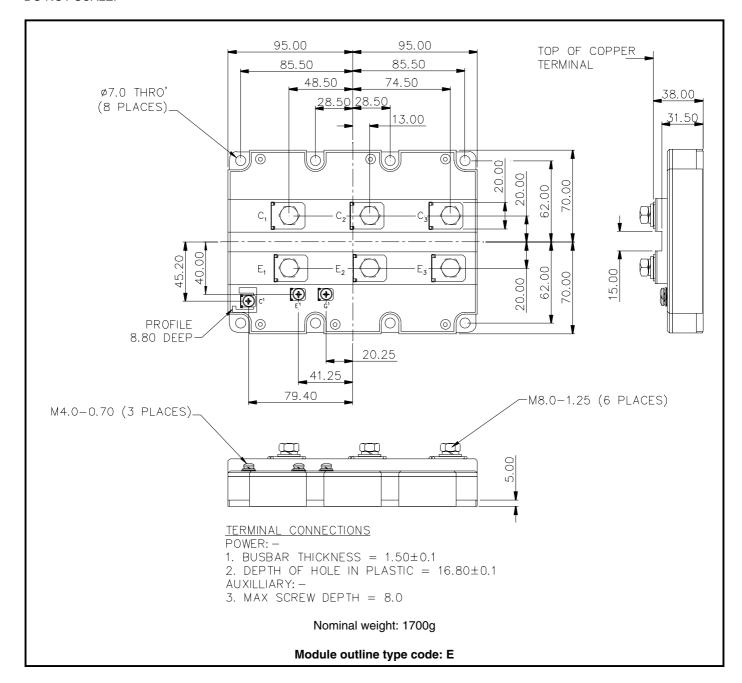


Fig. 12 DC current rating vs case temperature



### **PACKAGE DETAILS**

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.



#### POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

### **HEATSINKS**

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.



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